

## OptiMOS<sup>®</sup> Power-Transistor

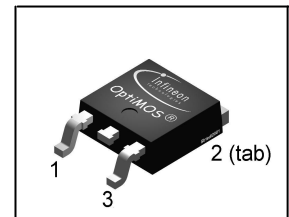
### Feature

- N-Channel
- Enhancement mode
- Logic Level
- Low On-Resistance  $R_{DS(on)}$
- Excellent Gate Charge x  $R_{DS(on)}$  product (FOM)
- Superior thermal resistance
- 175°C operating temperature
- Avalanche rated
- $dv/dt$  rated

### Product Summary

$V_{DS}$	30	V
$R_{DS(on)}$	10	m $\Omega$
$I_D$	30	A

P-TO252-3-11



Type	Package	Ordering Code	Marking
SPD30N03S2L-10	P-TO252-3-11	Q67042-S4030	2N03L10

### Maximum Ratings, at $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current <sup>1)</sup> $T_C=25^\circ\text{C}$	$I_D$	30 30	A
Pulsed drain current $T_C=25^\circ\text{C}$	$I_{D \text{ puls}}$	120	
Avalanche energy, single pulse $I_D=30 \text{ A}$ , $V_{DD}=25\text{V}$ , $R_{GS}=25\Omega$	$E_{AS}$	150	mJ
Repetitive avalanche energy, limited by $T_{jmax}^{2)}$	$E_{AR}$	10	
Reverse diode $dv/dt$ $I_S=30\text{A}$ , $V_{DS}=24\text{V}$ , $di/dt=200\text{A}/\mu\text{s}$ , $T_{jmax}=175^\circ\text{C}$	$dv/dt$	6	kV/ $\mu\text{s}$
Gate source voltage	$V_{GS}$	$\pm 20$	V
Power dissipation $T_C=25^\circ\text{C}$	$P_{tot}$	100	W
Operating and storage temperature	$T_j, T_{stg}$	-55... +175	$^\circ\text{C}$
IEC climatic category; DIN IEC 68-1		55/175/56	

**Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Characteristics</b>					
Thermal resistance, junction - case	$R_{thJC}$	-	1	1.5	K/W
Thermal resistance, junction - ambient, leaded	$R_{thJA}$	-	-	100	
SMD version, device on PCB: @ min. footprint @ 6 cm <sup>2</sup> cooling area <sup>3)</sup>	$R_{thJA}$	-	-	75 50	

**Electrical Characteristics, at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>Static Characteristics</b>					
Drain-source breakdown voltage $V_{GS}=0V, I_D=1mA$	$V_{(BR)DSS}$	30	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=50\mu A$	$V_{GS(th)}$	1.2	1.6	2	
Zero gate voltage drain current $V_{DS}=30V, V_{GS}=0V, T_j=25^\circ C$ $V_{DS}=30V, V_{GS}=0V, T_j=125^\circ C$	$I_{DSS}$	-	0.01 10	1 100	$\mu A$
Gate-source leakage current $V_{GS}=20V, V_{DS}=0V$	$I_{GSS}$	-	1	100	
Drain-source on-state resistance $V_{GS}=4.5V, I_D=30A$	$R_{DS(on)}$	-	11.2	14.6	$\Omega$
Drain-source on-state resistance $V_{GS}=10V, I_D=30$	$R_{DS(on)}$	-	7.8	10	m $\Omega$

<sup>1</sup>Current limited by bondwire ; with an  $R_{thJC} = 1.5K/W$  the chip is able to carry  $I_D = 76A$  at  $25^\circ C$ , for detailed information see app.-note ANPS071E available at [www.infineon.com/optimos](http://www.infineon.com/optimos)

<sup>2</sup>Defined by design. Not subject to production test.

<sup>3</sup>Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6cm<sup>2</sup> (one layer, 70  $\mu m$  thick) copper area for drain connection. PCB is vertical without blown air.

**Electrical Characteristics**

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Dynamic Characteristics**

Transconductance	$g_{fs}$	$V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ , $I_D = 30A$	23.8	47.5	-	S
Input capacitance	$C_{iss}$	$V_{GS} = 0V$ , $V_{DS} = 25V$ , $f = 1MHz$	-	1160	1550	pF
Output capacitance	$C_{oss}$		-	450	600	
Reverse transfer capacitance	$C_{rss}$		-	120	175	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 15V$ , $V_{GS} = 10V$ , $I_D = 30A$ , $R_G = 5.4\Omega$	-	6.1	9.2	ns
Rise time	$t_r$		-	13	20	
Turn-off delay time	$t_{d(off)}$		-	27	41	
Fall time	$t_f$		-	17	26	

**Gate Charge Characteristics**

Gate to source charge	$Q_{gs}$	$V_{DD} = 24V$ , $I_D = 30A$	-	3.7	4.9	nC
Gate to drain charge	$Q_{gd}$		-	10.9	16.3	
Gate charge total	$Q_g$	$V_{DD} = 24V$ , $I_D = 30A$ , $V_{GS} = 0$ to $10V$	-	31.4	41.8	
Gate plateau voltage	$V_{(plateau)}$	$V_{DD} = 24V$ , $I_D = 30A$	-	3.4	-	V

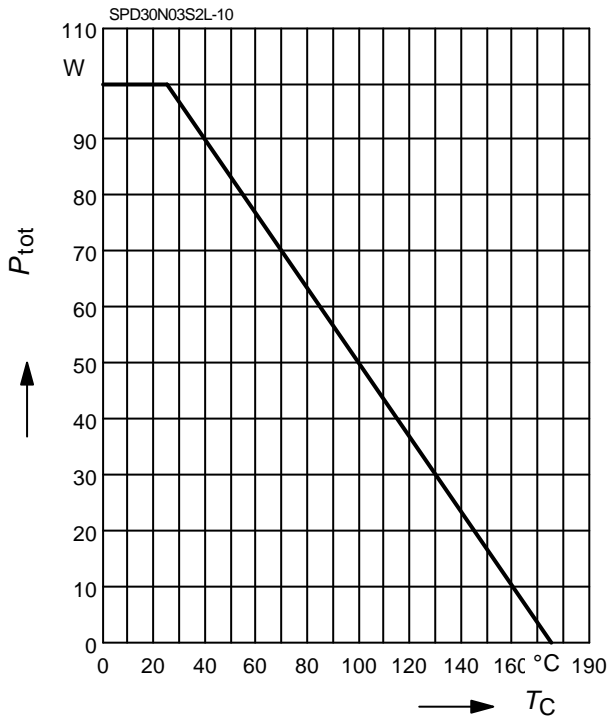
**Reverse Diode**

Inverse diode continuous forward current	$I_S$	$T_C = 25^\circ C$	-	-	30	A
Inv. diode direct current, pulsed	$I_{SM}$		-	-	120	
Inverse diode forward voltage	$V_{SD}$	$V_{GS} = 0V$ , $I_F = 30A$	-	0.9	1.2	V
Reverse recovery time	$t_{rr}$	$V_R = -V$ , $I_F = I_S$ , $di_F/dt = 100A/\mu s$	-	31	39	ns
Reverse recovery charge	$Q_{rr}$		-	29	37	

### 1 Power dissipation

$$P_{tot} = f(T_C)$$

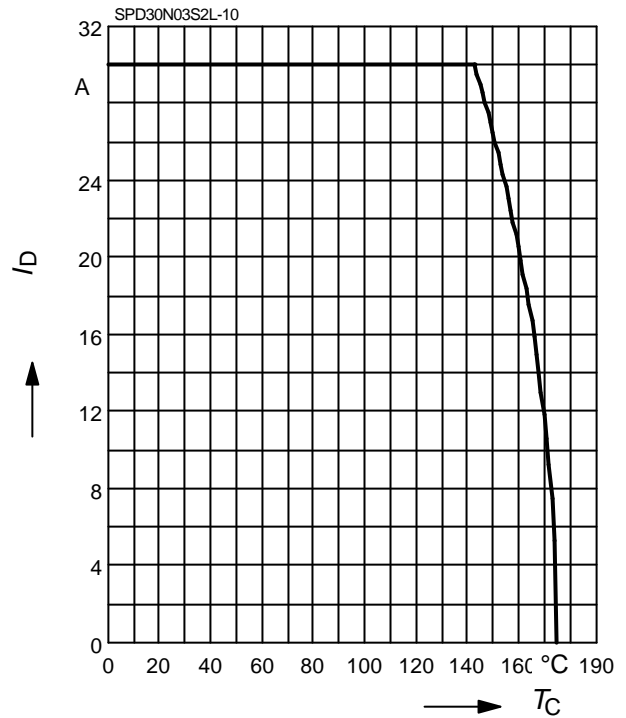
parameter:  $V_{GS} \geq 4 \text{ V}$



### 2 Drain current

$$I_D = f(T_C)$$

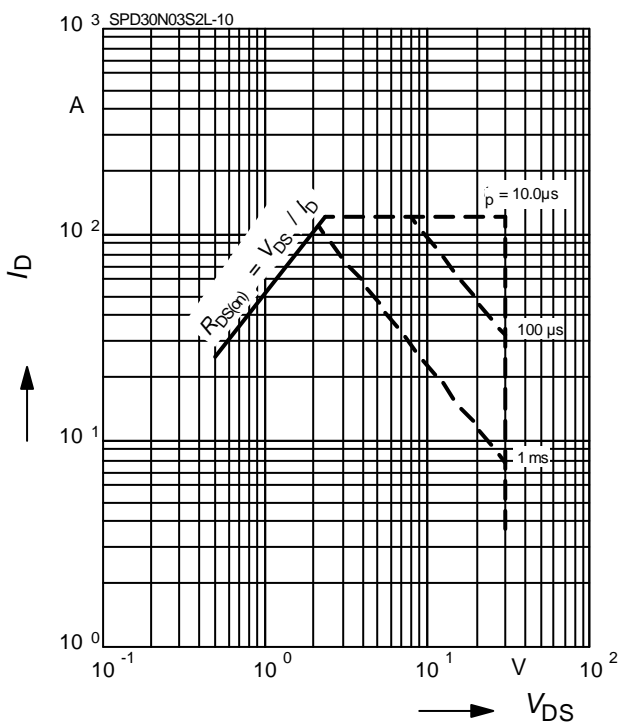
parameter:  $V_{GS} \geq 10 \text{ V}$



### 3 Safe operating area

$$I_D = f(V_{DS})$$

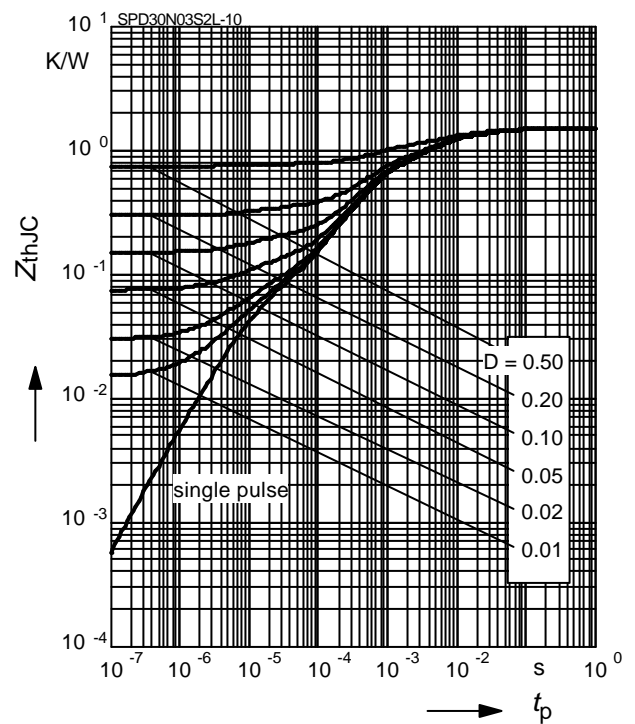
parameter:  $D = 0$ ,  $T_C = 25 \text{ °C}$



### 4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

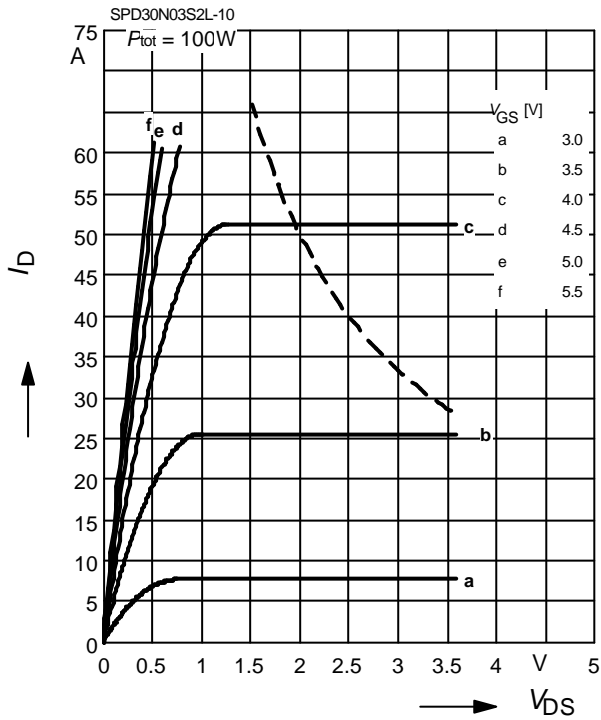
parameter:  $D = t_p/T$



**5 Typ. output characteristic**

$I_D = f(V_{DS}); T_J = 25^\circ\text{C}$

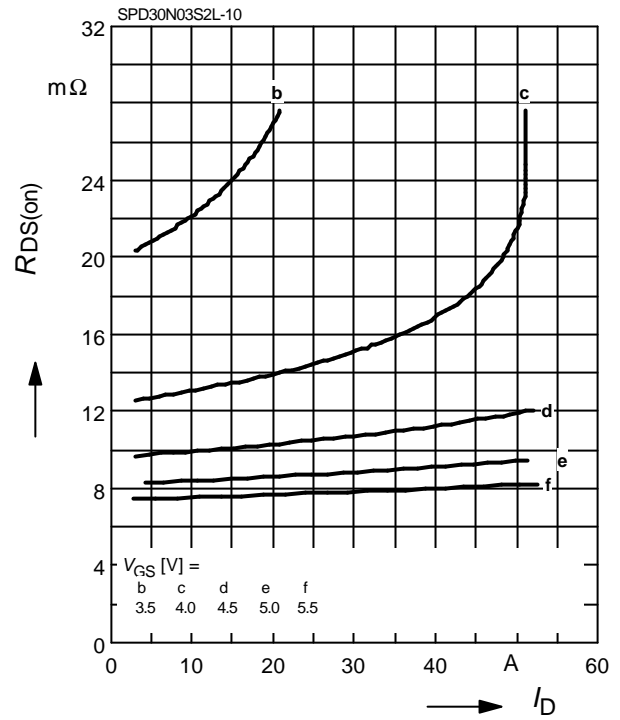
parameter:  $t_p = 80 \mu\text{s}$



**6 Typ. drain-source on resistance**

$R_{DS(on)} = f(I_D)$

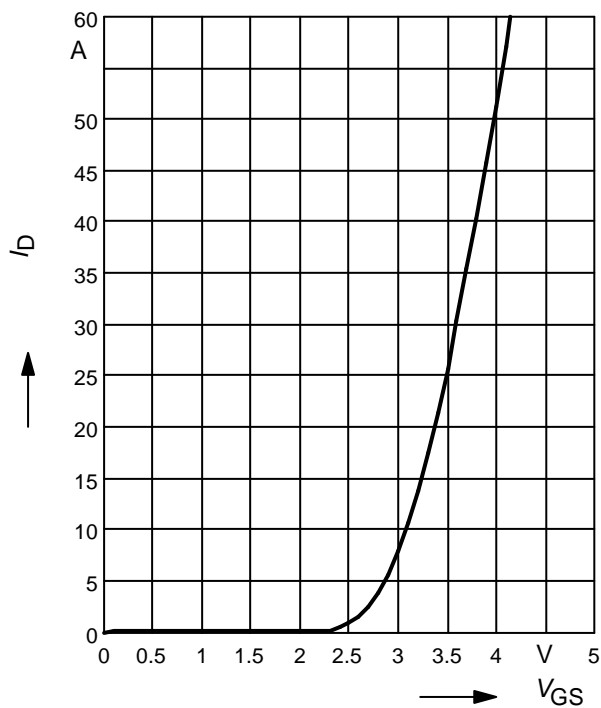
parameter:  $V_{GS}$



**7 Typ. transfer characteristics**

$I_D = f(V_{GS}); V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$

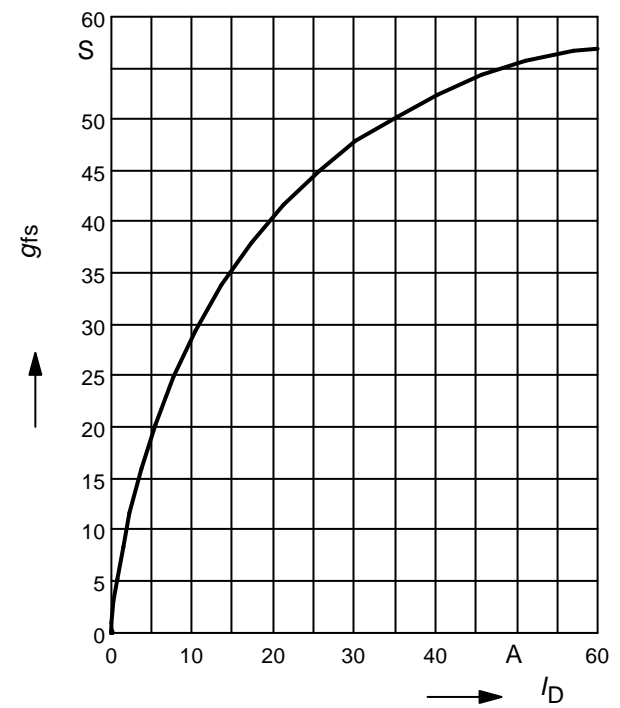
parameter:  $t_p = 80 \mu\text{s}$



**8 Typ. forward transconductance**

$g_{fs} = f(I_D); T_J = 25^\circ\text{C}$

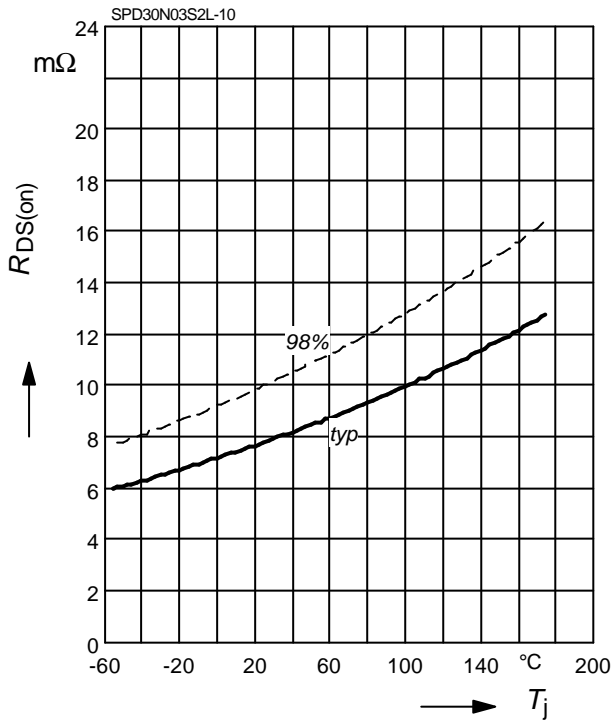
parameter:  $g_{fs}$



**9 Drain-source on-state resistance**

$$R_{DS(on)} = f(T_j)$$

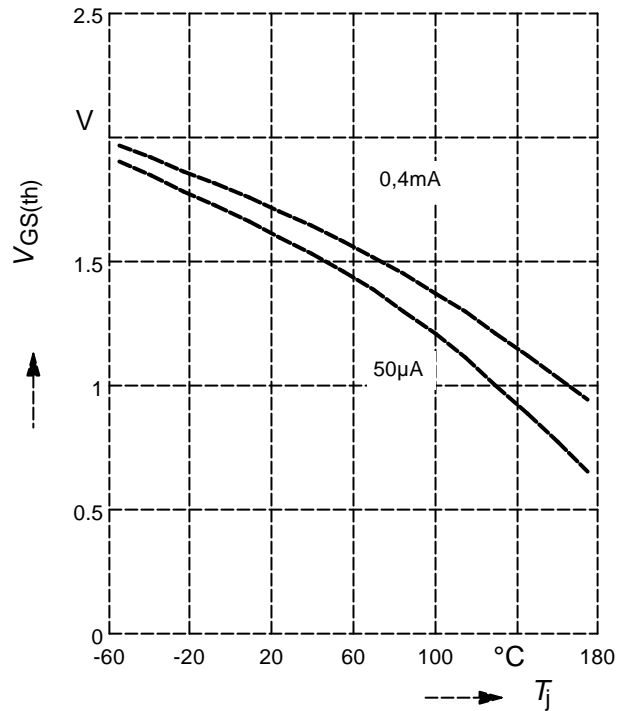
parameter :  $I_D = 30$  ,  $V_{GS} = 10$  V



**10 Typ. gate threshold voltage**

$$V_{GS(th)} = f(T_j)$$

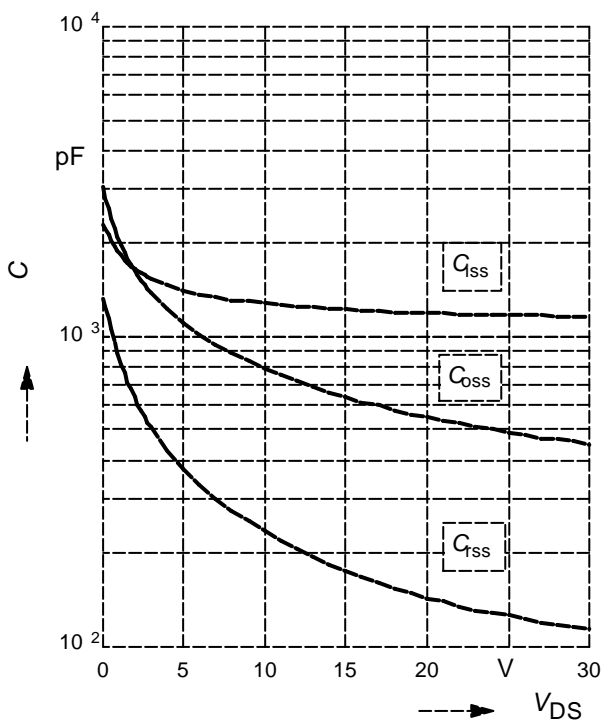
parameter:  $V_{GS} = V_{DS}$



**11 Typ. capacitances**

$$C = f(V_{DS})$$

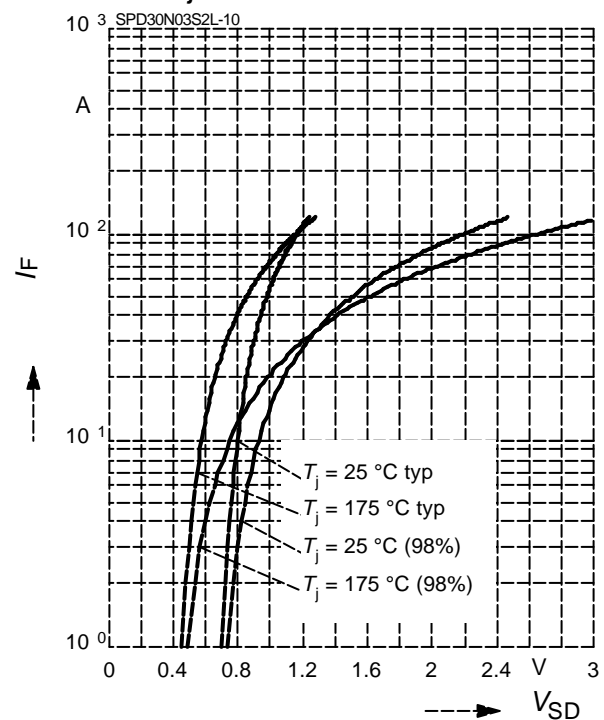
parameter:  $V_{GS}=0V$ ,  $f=1$  MHz



**12 Forward character. of reverse diode**

$$I_F = f(V_{SD})$$

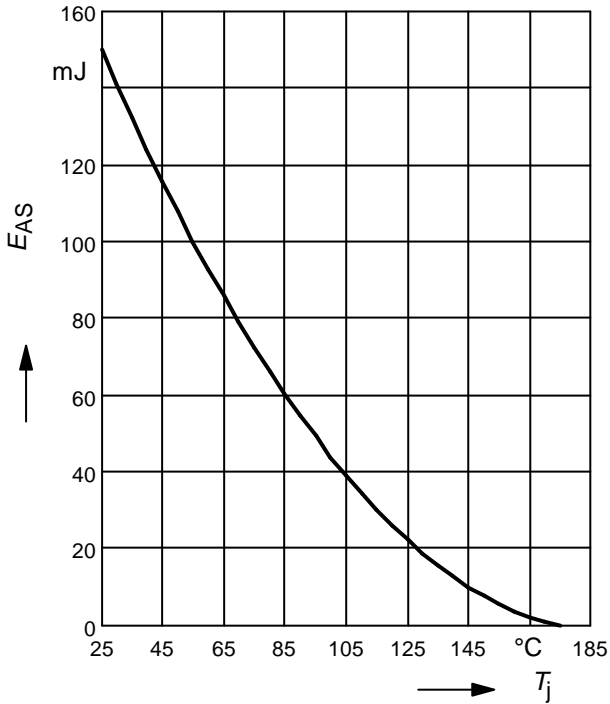
parameter:  $T_j$ ,  $t_p = 80$  µs



**13 Typ. avalanche energy**

$$E_{AS} = f(T_j)$$

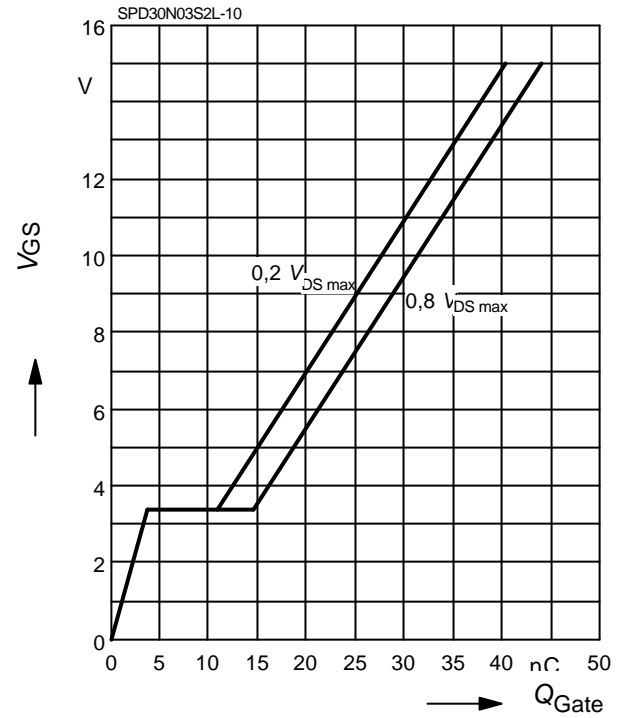
par.:  $I_D = 30\text{ A}$  ,  $V_{DD} = 25\text{ V}$  ,  $R_{GS} = 25\ \Omega$



**14 Typ. gate charge**

$$V_{GS} = f(Q_{Gate})$$

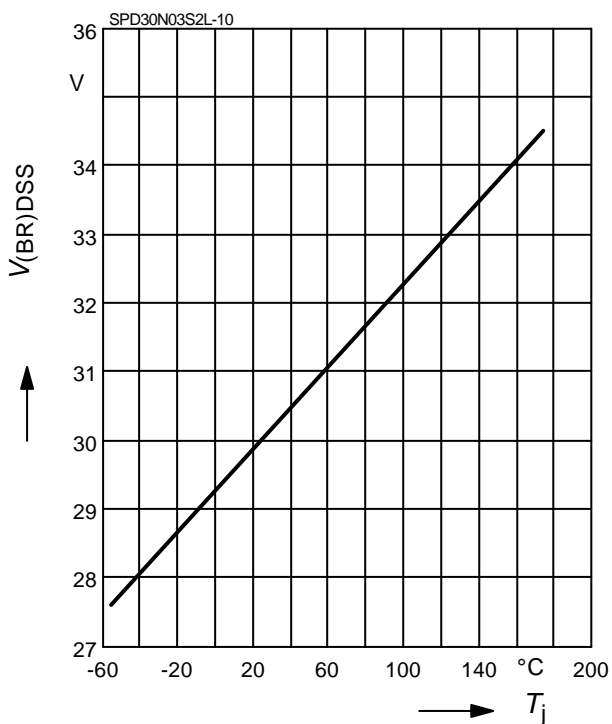
parameter:  $I_D = 30\text{ A}$  pulsed



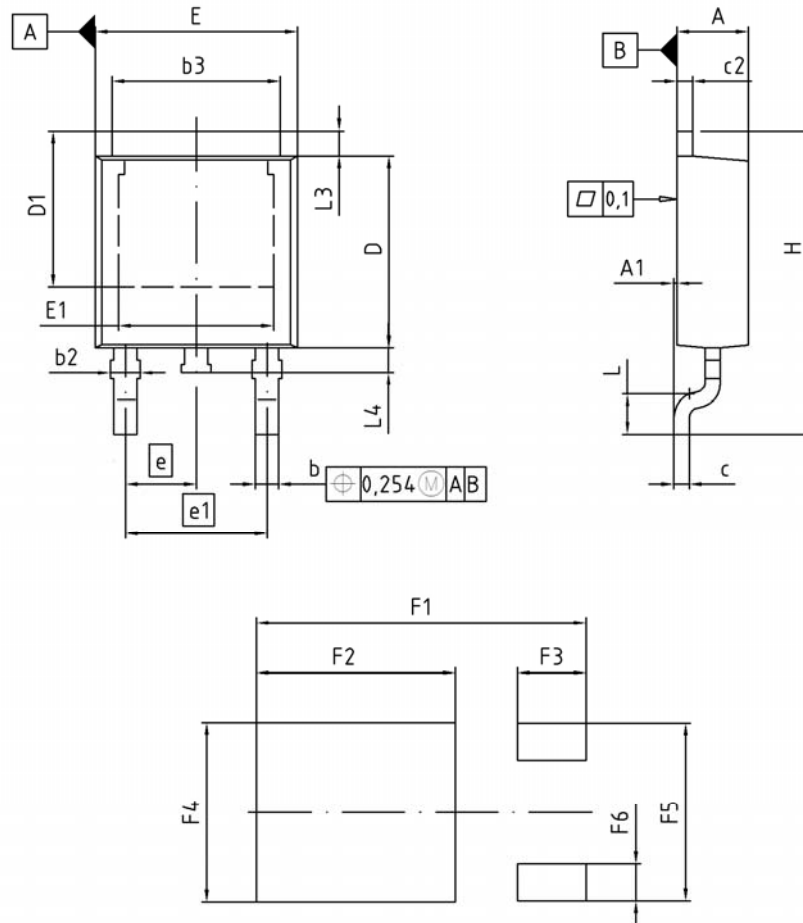
**15 Drain-source breakdown voltage**

$$V_{(BR)DSS} = f(T_j)$$

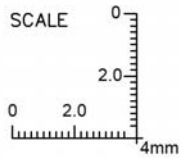
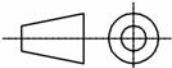
parameter:  $I_D = 10\text{ mA}$



## Package outline: PG-TO252-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.16	2.41	0.085	0.095
A1	0.00	0.15	0.000	0.006
b	0.64	0.89	0.025	0.035
b2	0.65	1.15	0.026	0.045
b3	5.00	5.50	0.197	0.217
c	0.46	0.60	0.018	0.024
c2	0.46	0.98	0.018	0.039
D	5.97	6.22	0.235	0.245
D1	5.02	5.84	0.198	0.230
E	6.40	6.73	0.252	0.265
E1	4.70	5.21	0.185	0.205
e	2.29		0.090	
e1	4.57		0.180	
N	3		3	
H	9.40	10.48	0.370	0.413
L	1.18	1.70	0.046	0.067
L3	0.90	1.25	0.035	0.049
L4	0.51	1.00	0.020	0.039
F1	10.50	10.70	0.413	0.421
F2	6.30	6.50	0.248	0.256
F3	2.10	2.30	0.083	0.091
F4	5.70	5.90	0.224	0.232
F5	5.66	5.86	0.223	0.231
F6	1.10	1.30	0.043	0.051

DOCUMENT NO. Z8B00003328
SCALE 
EUROPEAN PROJECTION 
ISSUE DATE 19-10-2007
REVISION 03



**Published by**  
**Infineon Technologies AG**  
**81726 Munich, Germany**  
**© 2008 Infineon Technologies AG**  
**All Rights Reserved.**

**Legal Disclaimer**

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

**Information**

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office ([www.infineon.com](http://www.infineon.com)).

**Warnings**

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.